

# A Collaborative Machine Learning Approach to Fast and High-Fidelity Design Prediction

*Task 2810.021*

*Jiang Hu*

*Dept of ECE*

*Texas A&M University*

*Task 2810.022*

*Yiran Chen*

*Dept of ECE*

*Duke University*



# Task Overview



- Center: Texas Analog Center of Excellence (TxACE)
- Thrust: Computer-Aided Design and Test (CADT)
- Subthrust: System, Logic and Physical Design (SLPD)
- Task leaders
  - Jiang Hu, Texas A&M Univ, Task 2810.021
  - Yiran Chen, Duke Univ, Task 2810.022
- Start date: January 1, 2019
- Industrial liaisons
  - Gi-Joon Nam, IBM
  - Xiaoqing Xu, ARM
  - Divya Prasad, ARM
  - Savithri Sundareswaran, NXP

- Machine learning-based techniques for fast and high-fidelity prediction of
  - circuit routability
  - timing
  - power
  - crosstalk noise
- Routability/crosstalk predictions will be useful for analog and mixed-signal designs
- Will show how the predictions improve macro/cell placement and system level models

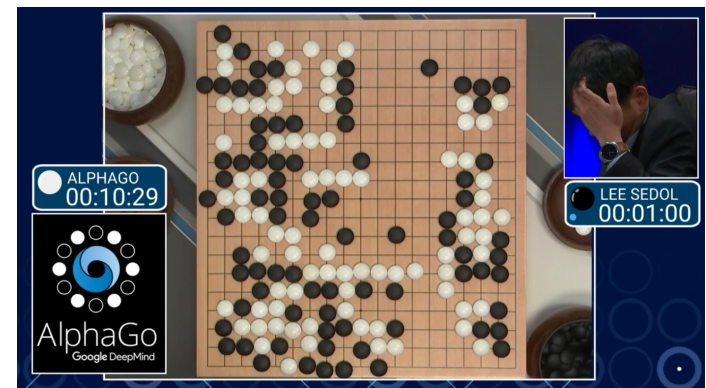


# Planned Deliverables

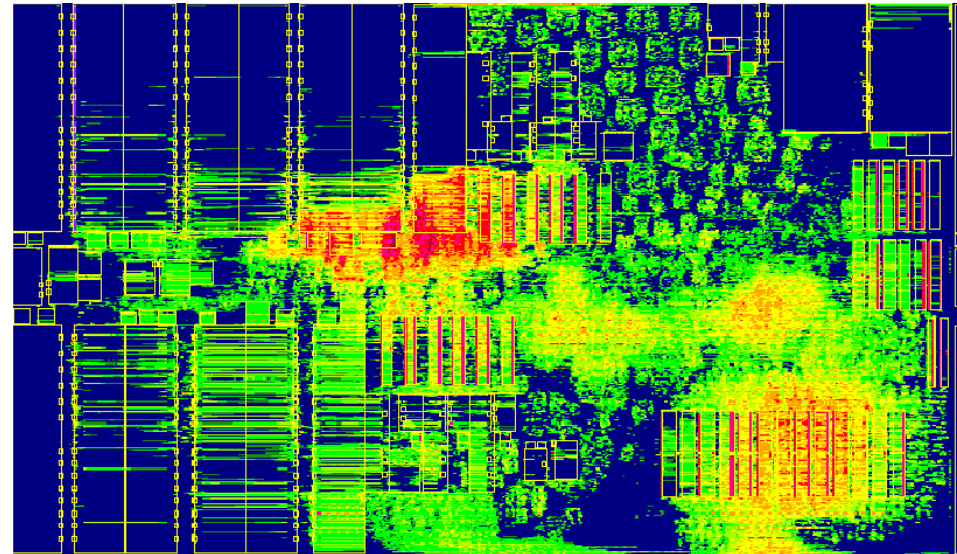


- Machine learning-based early routability prediction for digital and analog IC designs. (12/2019)
- Machine learning-based early timing prediction for digital IC designs. (12/2019)
- Machine learning-based early crosstalk noise prediction for digital and analog IC designs. (12/2020)
- Machine learning-based early power prediction for digital IC designs. (12/2020)
- Machine learning-guided placement for routability, timing, power and signal integrity improvement. (12/2021)
- Application of machine learning-based prediction in system-level models for hardware IPs. (12/2021)

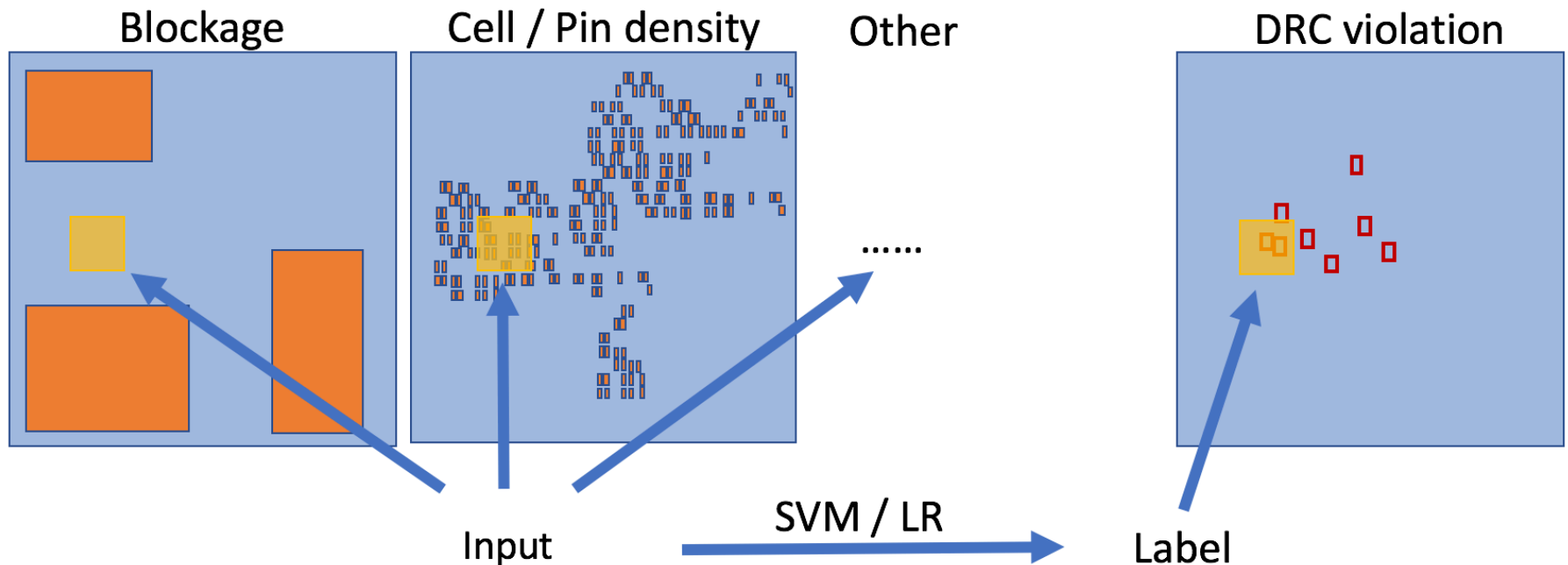
- Decisions in early design steps have large impact
- Need fast and high-fidelity predictions
- Existing techniques
  - Analytical: fast but inaccurate
  - Trial design: accurate but very slow
- Machine learning
  - Extracting design knowledge from data
  - Emulating design experience



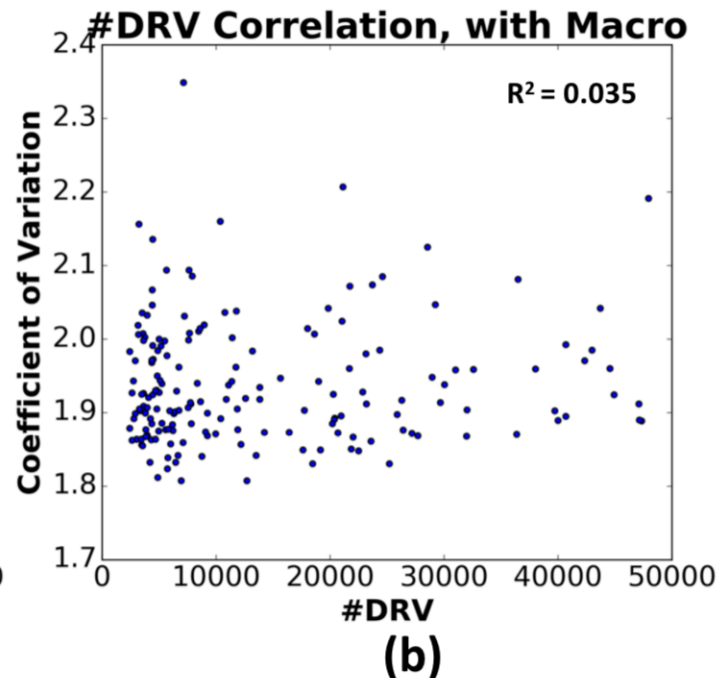
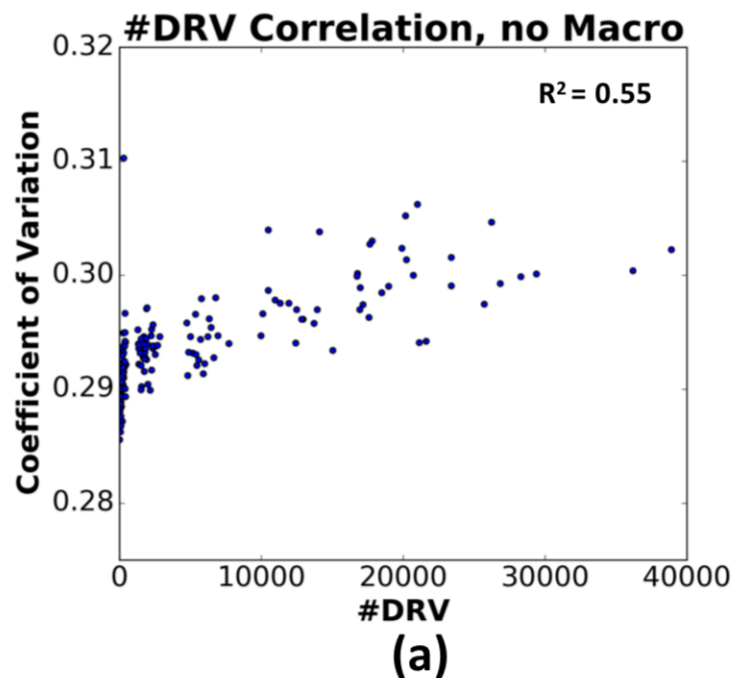
- Routability: post-routing design rule violations
- Early prediction at placement stage
- Analytical techniques
  - Very fast
  - Not enough fidelity
- Trial routing
  - Acceptable fidelity
  - Not fast enough



Learning on *small cropped regions*



- Layout is less homogeneous
- Correlation between pin density and #DRV becomes weak

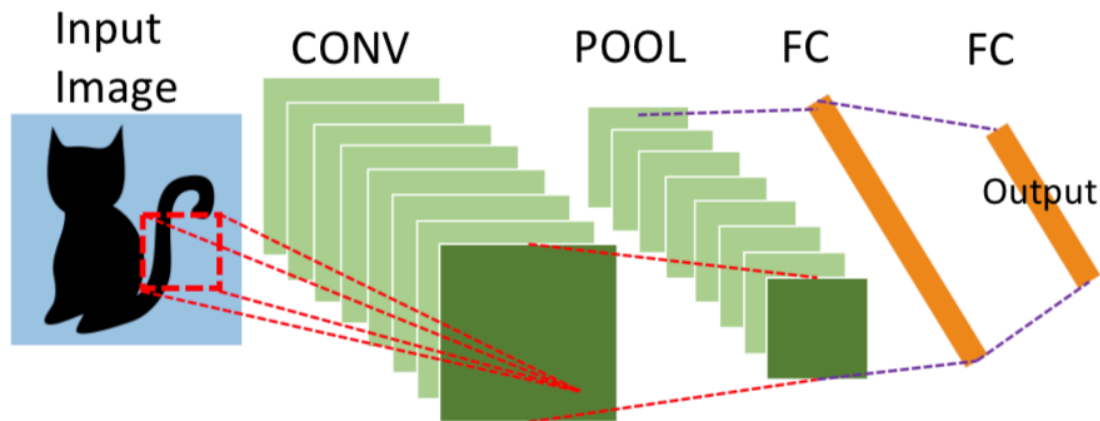


Each point corresponds to one placement



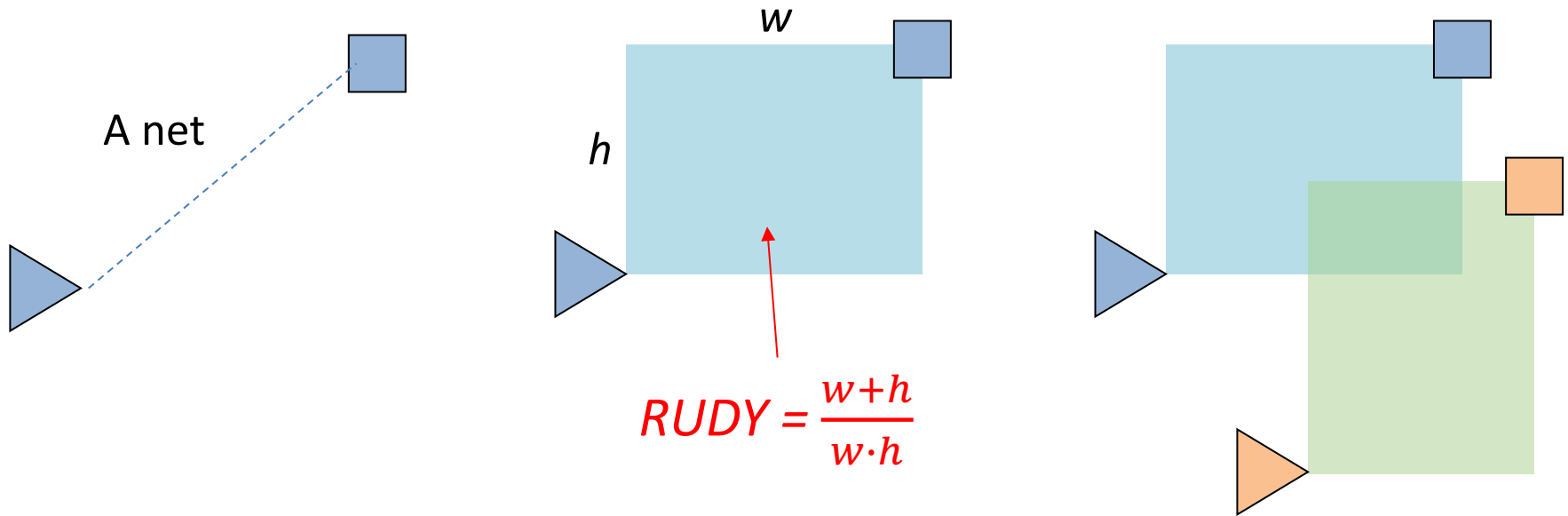
- Predicting overall number of design rule violations (#DRV)
  - Given two placement solutions, tell which is more routable with high fidelity
- DRV hotspot detection
  - Given a relatively routable placement solution, pinpoint DRV hotspots such that mitigation measures are well targeted

Given a cell placement, classify it among four routability levels,  $c_0, c_1, c_2, c_3$ ,  $c_0$  has the least #DRVs

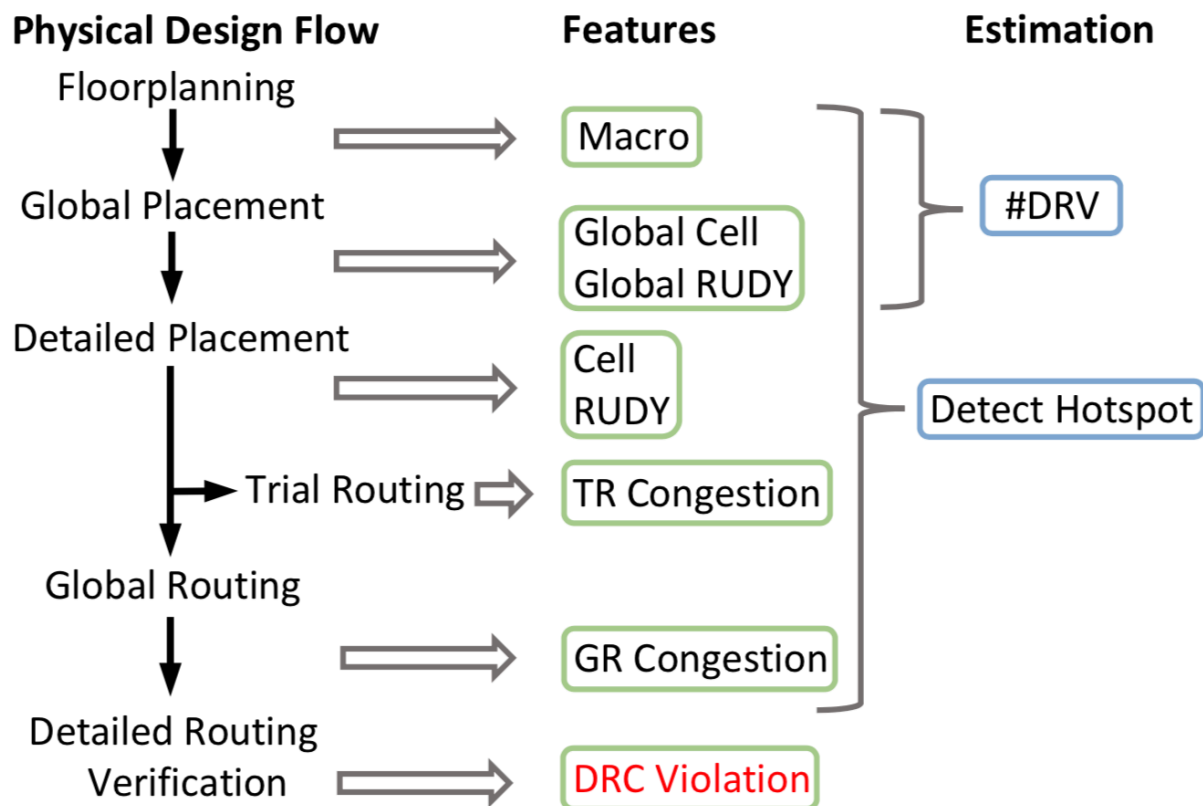


Convolutional (CONV), Pooling (POOL) and Fully Connected (FC) layers  
Widely used in image classification

- RUDY (Rectangular Uniform wire DensitY) (P. Spinder et al. DATE07)
- RUDY at a point is superposition of RUDYs of multiple nets

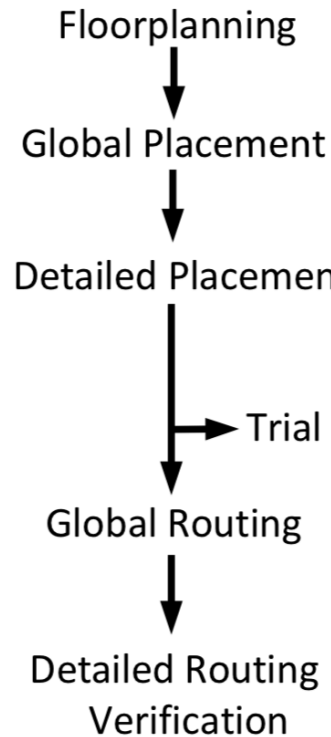


- Macro:
  - region occupied by macros
  - density of macro pins in each layer
- Cell:
  - density of cells
  - density of cell pins
- Global cell:
  - cell features at global placement
- Global RUDY:
  - RUDY features calculated by global placement results

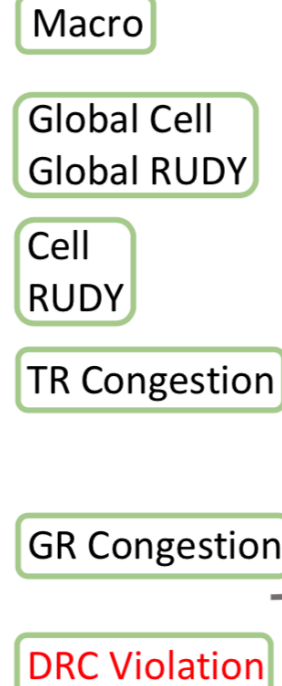


- RUDY
  - long-range RUDY
    - RUDY from long-range nets
  - short-range RUDY
    - DURY from short-range nets
  - RUDY pins
    - pins with density value equal to the RUDY value of its net
- Congestion
  - trial global routing congestion
  - global routing congestion
- DRC violation
  - prediction target / label

## Physical Design Flow



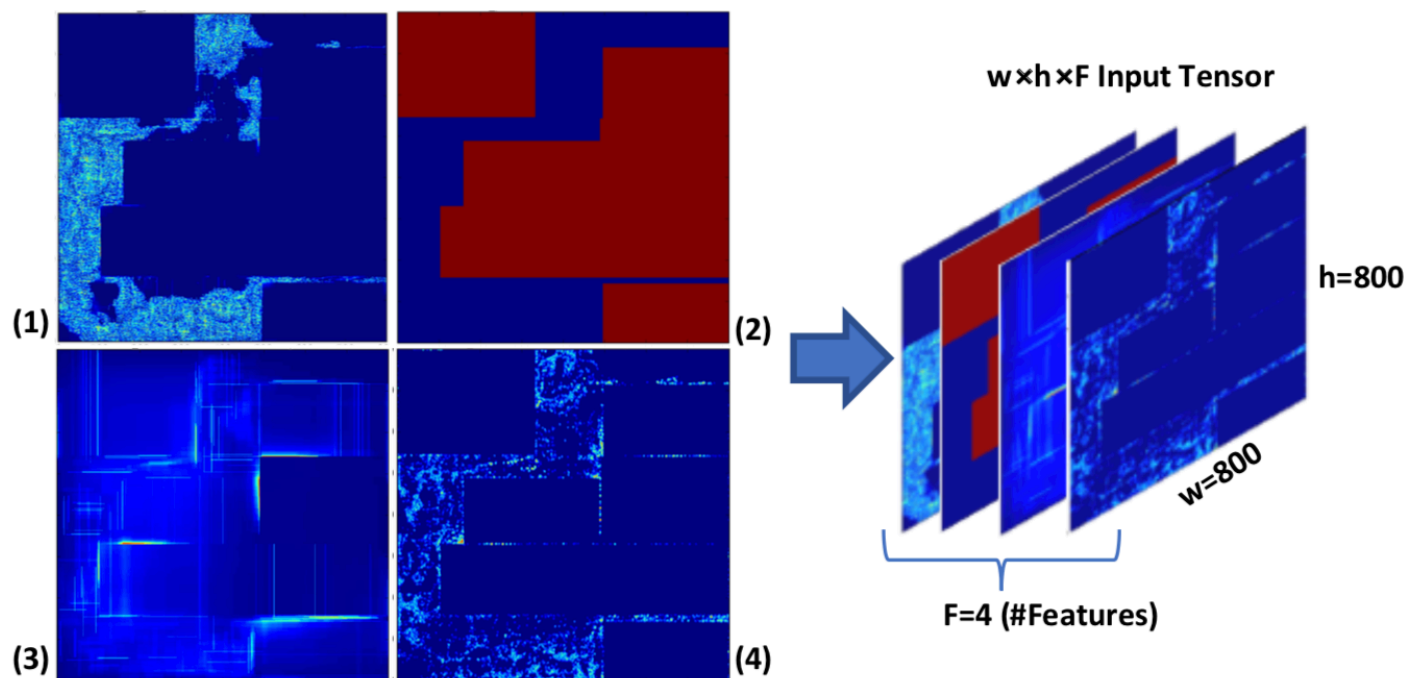
## Features



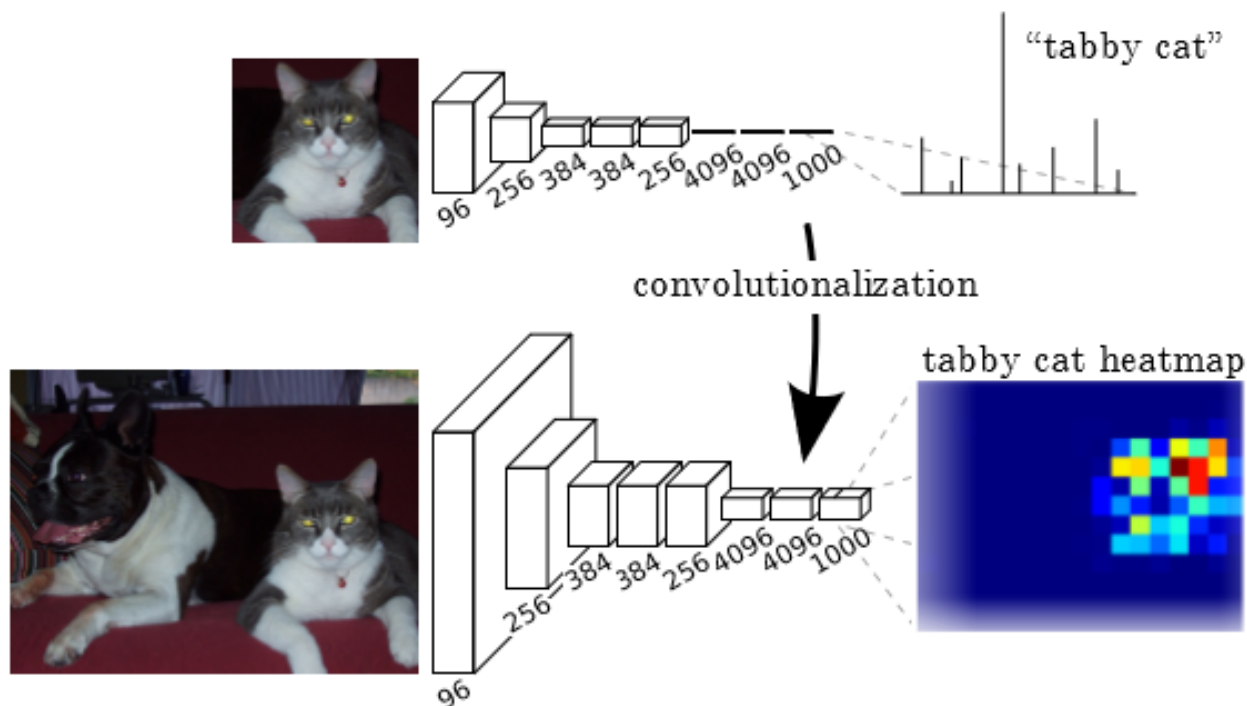
## Estimation

#DRV

Detect Hotspot



Input tensor constructed by stacking 2D features:  
(1) Pin density, (2) macro (3) long-range RUDY, (4) RUDY pins



Eliminate FC layers

May use transposed-convolutional to up-sample

Used in image segmentation, object detection

- Five designs from ISPD 2015 placement contest, 45nm technology
- ~300 different placements by placing macros in different ways
- Placement, routing and DRC are done by Cadence tool
- When a circuit is tested, the model trained with the other circuits
- SVM and Logistic Regression (LR) methods for comparison

Circuit Name	#Macros	#Cells	#Nets	Width ( $\mu\text{m}$ )	#Placements
des_perf	4	108288	110283	900	600
edit_dist	6	127413	131134	800	300
fft	6	30625	32088	800	300
matrix_mult_a	5	149650	154284	1500	300
matrix_mult_b	7	146435	151614	1500	300

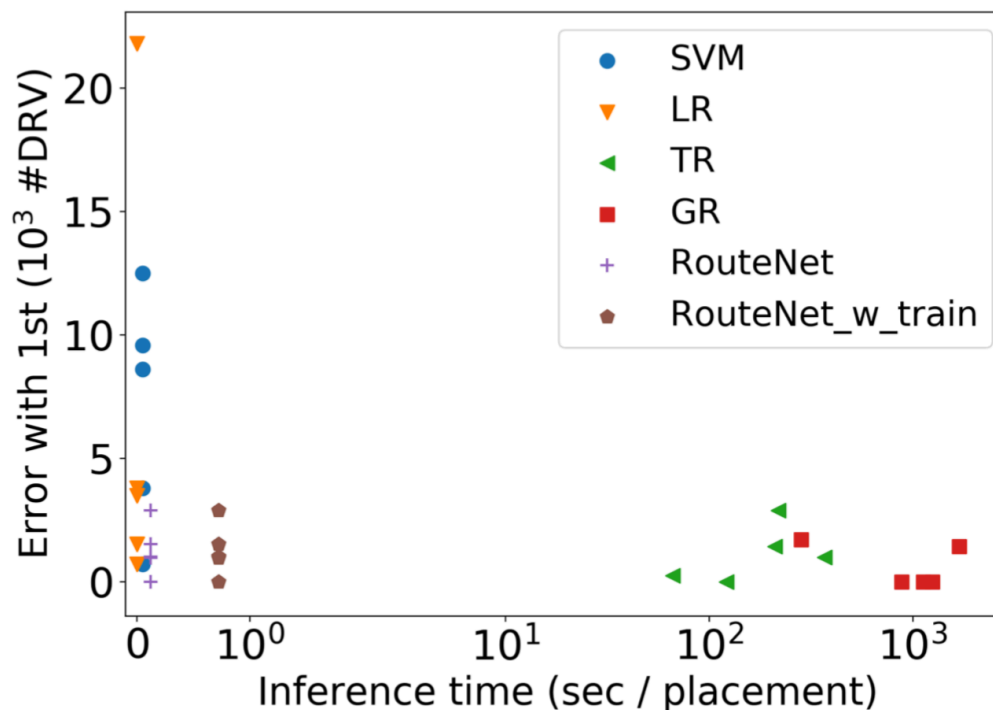


- How recognize placements with the lowest #DRV level ( $c_0$ )
- The **best rank** of top ten placements predicted to have least #DRV

Circuit Name	$c_0/c_1+c_2+c_3$ accuracy (%)					Best rank in top 10				
	SVM	LR	TR	GR	Route Net	SVM	LR	TR	GR	Route Net
des_perf	63	74	80	77	80	87 <sup>th</sup>	15 <sup>th</sup>	2 <sup>nd</sup>	1 <sup>st</sup>	2 <sup>nd</sup>
edit_dist	69	68	78	77	76	17 <sup>th</sup>	17 <sup>th</sup>	3 <sup>rd</sup>	3 <sup>rd</sup>	2 <sup>nd</sup>
fft	66	62	73	70	75	6 <sup>th</sup>	6 <sup>th</sup>	2 <sup>nd</sup>	33 <sup>rd</sup>	1 <sup>st</sup>
matrix_mult_a	66	65	78	74	72	30 <sup>th</sup>	5 <sup>th</sup>	1 <sup>st</sup>	1 <sup>st</sup>	5 <sup>th</sup>
matrix_mult_b	63	62	76	73	76	22 <sup>nd</sup>	93 <sup>rd</sup>	4 <sup>th</sup>	1 <sup>st</sup>	4 <sup>th</sup>
Average	65	66	77	74	76	32 <sup>nd</sup>	27 <sup>th</sup>	2 <sup>nd</sup>	8 <sup>th</sup>	3 <sup>rd</sup>

TR: Trial Routing

GR: Global Routing



- Y: gap between the 'best in 10' and the actually 1st-ranked placement with least #DRV
- X: inference time
- **RouteNet** achieves low inference time and high accuracy at the same time

- Same decision threshold is used for all designs
- Slight different False Positive Rate (FPR), all under 1%
- **RouteNet** has the highest True Positive Rate (TPR)

Circuit Name	FPR (%)	TPR (%)				RouteNet
		TR	GR	LR	SVM	
des_perf	0.54	17	56	54	42	74
edit_dist	1.00	25	36	38	28	64
fft	0.30	21	45	54	31	71
matrix_mult_a	0.21	13	30	34	12	49
matrix_mult_b	0.24	13	37	41	20	53
Average	0.46	18	41	44	27	62



# Future Plan for Year 1



- Improving routability prediction by considering pin access
- Routability prediction for analog and mixed-signal IC designs
- Pre-routing timing prediction



# Students on Task 2810.021, 2810.022



- Zhiyao Xie, Duke University, expected graduation: 2021
- Rongjian Liang, TAMU, expected graduation: 2021
- Planned internship: Rongjian Liang, IBM, summer 2019



# Interactions with SRC Companies



- Regular web meetings with IBM
- Site visit to ARM
- Site visit to Mentor Graphics
- Web meeting with NXP

***Thank You!***